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	Application No.	Applicant(s)		
Notice of Allowability	10/567,358	NAKATA ET AL.		
	Examiner	Art Unit		
	Dameon E. Levi	2841		
The MAILING DATE of this communication appeal claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	olication. If not includ will be mailed in due	ed course. THIS	
1. \boxtimes This communication is responsive to <u>09/19/2007</u> .				
2. 🔀 The allowed claim(s) is/are <u>1 and 2</u> .			,	
3. Acknowledgment is made of a claim for foreign priority ur a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority do	e been received. e been received in Application No cuments have been received in this a of this communication to file a reply MENT of this application. iitted. Note the attached EXAMINER' es reason(s) why the oath or declara st be submitted. son's Patent Drawing Review (PTO-	national stage application of National stage application of Nation is deficient.	quirements	
Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the sheet in the sh	.84(c)) should be written on the drawir	ngs in the front (not the	e back) of	
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.				
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Attachment(s)				
1. Notice of References Cited (PTO-892) ,	5. Notice of Informal P			
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summary Paper No./Mail Date	te		
3. Information Disclosure Statements (PTO/SB/08), 7. Examiner's Amendment/Comment Paper No./Mail Date 02/06/2006				
4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. 🛛 Examiner's Stateme	8. ⊠ Examiner's Statement of Reasons for Allowance .		
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DETAILED ACTION

Allowable Subject Matter

Claims 1 and 2 are allowable.

The following is an examiner's statement of reasons for allowance: In response to remarks and claim amendments made in Applicants' Request for Continued Examination submitted 09/19/2007, and, upon conclusion of a comprehensive search of the pertinent prior art, the Office indicates that the claims, as amended, are allowable. Regarding independent claim 1, patentability exists, at least in part, with the claimed features of, one or more semiconductor mounting paste guide paths are formed in the mounting pads; a broad section for pressing out and spreading uniformly the semiconductor mounting paste for connecting to an IC chip is formed in a part of the pad clearance gap; and a thin film layer is formed in a center section of the broad section.

A careful examination of the prior art of record, Ikefuji et al, does not adequately teach or disclose all of the limitations above, arranged and disposed in the same manner as claimed by the Applicants.

Applicant's Arguments regarding first embodiment of Ikefuji, solder bumps disposed at precisely the locations of the terminals are used to connect the IC chip to the substrate. This solder is in no way disposed in a gap between terminals. Ikefuji clearly describes the goal of avoiding a short circuit of the coils 12, and if the solder were disposed between the terminals, this would cause a short circuit.

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In the second embodiment of Ikefuji, an anisotropic film 19 is used to connect the IC chip to the substrate. This anisotropic film does not have a viscosity which enables it to flow, and therefore, no semiconductor mounting paste guide path is needed.

There is no disclosure or suggestion of any semiconductor mounting paste in either the third or fourth embodiment of Ikefuji. Additionally, Ikefuji fails to disclose or suggest any thin film applied to any central portion of a broad section. The arguments were found to be persuasive.

The pertinent prior art, when taken alone, or, in combination, does not adequately teach or suggest all of the limitations as claimed by the Applicants.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dameon E. Levi whose telephone number is (571) 272-2105. The examiner can normally be reached on Mon.-Thurs. (9:00 - 5:00) IFP, Fridays Telework.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Dean Reichard can be reached on (571) 272-1984. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Dameon E Levi Examiner Art Unit 2841

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DEAN A. REICHARD /

SUPERVISORY PATENT EXAMINER

TECHNOLOGY CENTER 2800